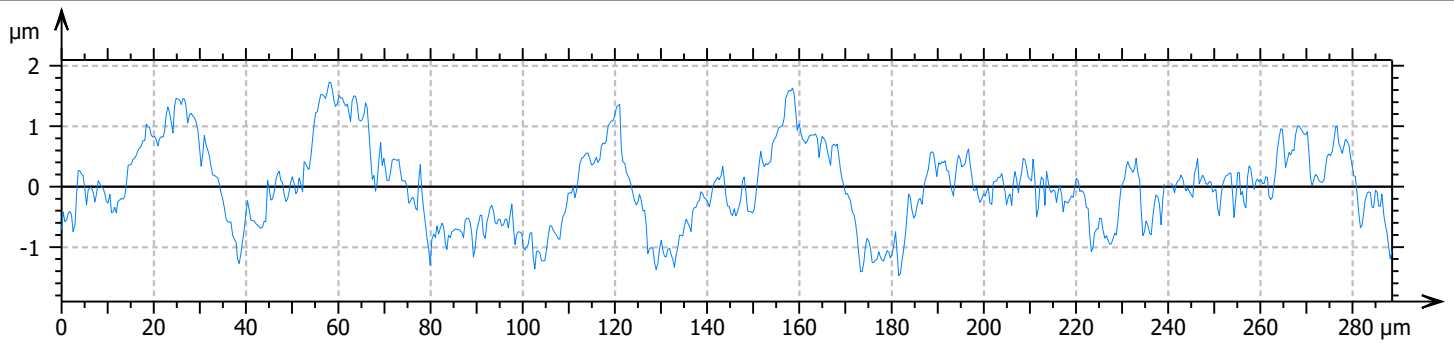


Parameters	Value	Unit
Length	288.6	µm



Parameters	Value	Unit
Length	288.5	µm

ISO 4287 - Roughness (S-L)

F: None

S-filter (λ_s): None

L-filter (λ_c): Gaussian, 0.25 mm, Ends not cut

Evaluation length: All λ_c (1)

Amplitude parameters

Rp	2.153	µm	
Rv	1.307	µm	
Rz	3.460	µm	
Rc	1.113	µm	No averaging (single value)
Rt	3.460	µm	
Ra	0.4819	µm	
Rq	0.6216	µm	
Rsk	0.9361		
Rku	4.063		

Material ratio parameters

Rmr	5.248	%	$c = 1 \mu\text{m}$ below highest peak
Rdc	0.9623	µm	$p = 20\%$, $q = 80\%$

Information

The studiable contains non-measured points. The results are calcula...

Warnings

The workflow already contains a 'Metrological filter' operator.

ISO 4287 - Roughness (S-L)

F: None

S-filter (λ_s): None

L-filter (λ_c): Gaussian, 0.25 mm

Evaluation length: All λ_c (1)

Amplitude parameters

Rp	1.750	µm	
Rv	1.402	µm	
Rz	3.152	µm	
Rc	1.068	µm	No averaging (single value)
Rt	3.152	µm	
Ra	0.5534	µm	
Rq	0.6858	µm	
Rsk	0.3353		
Rku	2.505		

Material ratio parameters

Rmr	15.17	%	$c = 1 \mu\text{m}$ below highest peak
Rdc	1.216	µm	$p = 20\%$, $q = 80\%$

Information

The studiable contains non-measured points. The results are calcula...

Warnings

The workflow already contains a 'Metrological filter' operator.

ISO 25178 - Primary surface

F: [Workflow] Leveled (LS-plane)

F: Leveled (LS), Angle $-7.333e-05^\circ$, $-5.252e-05^\circ$

S-filter (λ_s): Gaussian, $0.8 \mu\text{m}$

Height parameters

Sq	1.236	μm
Ssk	-0.008798	
Sku	3.112	
Sp	9.322	μm
Sv	5.059	μm
Sz	14.38	μm
Sa	0.9899	μm

Information

The studiable contains non-measured points. The results are calcula...

